



XRD6406

CMOS

6 MSPS, 10-Bit, High Speed
Analog-to-Digital Converter

FEATURES

- 10-Bit Resolution
- Sampling Rate to 6 MSPS
- DNL = ± 1 LSB, INL = ± 2 LSB
- Internal S/H Function
- Single 5V Power Supply
- V_{IN} DC Range: 0V to V_{DD}
- V_{REF} DC Range: 1V to V_{DD}
- Low Power: 65mW
- Three-State Digital Outputs
- Latch-Up Free
- Pin Compatible With: MP8784

APPLICATIONS

June 1998-2

- Digital Color Copiers
- Precision CCDs and Scanners
- Digital Radio

BENEFITS

- Simplified Analog Design
- Rugged
- Few External Components, no S/H Needed
- Reduced Board Space

GENERAL DESCRIPTION

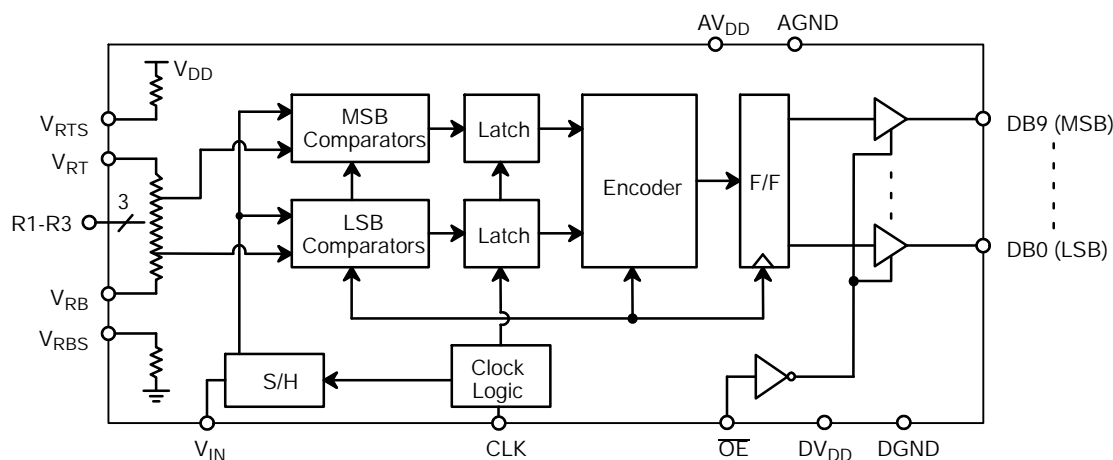
The XRD6406 is a 10-bit, 6 MSPS, Analog-to-Digital Converter for applications that require high speed and high accuracy. Designed using an advanced CMOS process, this part offers excellent performance, low power consumption and latch-up free operation.

The XRD6406 uses a subranging architecture to maintain low power consumption at high conversion rates. Our proprietary comparator design achieves a low analog input capacitance. The input circuitry of the XRD6406 includes an on-chip S/H function that allows this part to digitize analog input signals between AGND and AV_{DD} .

The designer can choose the internally generated reference voltages, or provide external reference voltages to the V_{RB} and V_{RT} pins. The internal reference generates 1.0V at V_{RB} and 4V at V_{RT} . Providing external reference voltages allows easy interface to any input signal range between GND and V_{DD} . This also allows the system to cancel zero scale and full scale errors. The Reference Ladder taps (R1 to R3) can be used to externally trim any INL errors.

This device operates from a single 5V supply. Power consumption from a 5V supply is typically 65mW at $F_S=6$ MHz.

SIMPLIFIED BLOCK DIAGRAM



Rev. 1.00

E1998

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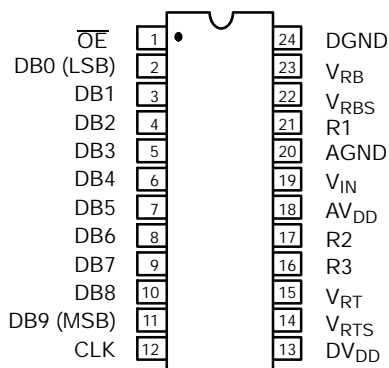


ORDERING INFORMATION

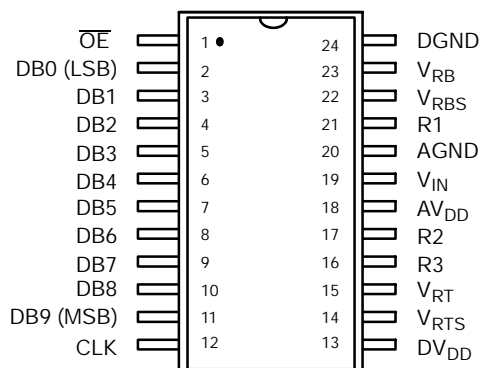
| Package Type | Temperature Range | Part No. | DNL (LSB) | INL (LSB) |
|--------------|-------------------|------------|-----------|-----------|
| Plastic Dip | -40 to +85°C | XRD6406AIP | 1 | 2 |
| SOIC | -40 to +85°C | XRD6406AID | 1 | 2 |

PIN CONFIGURATIONS

See Packaging Section for Package Dimensions



24 Pin PDIP (0.300")



24 Pin SOIC (Jedec, 0.300")

PIN OUT DEFINITIONS

| PIN NO. | NAME | DESCRIPTION |
|---------|------|-------------------------|
| 1 | OE | Output Enable |
| 2 | DB0 | Data Output Bit 0 (LSB) |
| 3 | DB1 | Data Output Bit 1 |
| 4 | DB2 | Data Output Bit 2 |
| 5 | DB3 | Data Output Bit 3 |
| 6 | DB4 | Data Output Bit 4 |
| 7 | DB5 | Data Output Bit 5 |
| 8 | DB6 | Data Output Bit 6 |
| 9 | DB7 | Data Output Bit 7 |
| 10 | DB8 | Data Output Bit 8 |
| 11 | DB9 | Data Output Bit 9 (MSB) |
| 12 | CLK | Clock Input |

| PIN NO. | NAME | DESCRIPTION |
|---------|------------------|---------------------------|
| 13 | DV _{DD} | Digital Power Supply |
| 14 | V _{RTS} | Top Internal Reference |
| 15 | V _{RT} | Top of Reference |
| 16 | R3 | 3/4 Reference Tap Point |
| 17 | R2 | 1/2 Reference Tap Point |
| 18 | AV _{DD} | Analog Power Supply |
| 19 | V _{IN} | Analog Input Voltage |
| 20 | AGND | Analog Ground |
| 21 | R1 | 1/4 Reference Tap Point |
| 22 | V _{RBS} | Bottom Internal Reference |
| 23 | V _{RB} | Bottom of Reference |
| 24 | DGND | Digital Ground |

ELECTRICAL CHARACTERISTICS TABLE

Unless Otherwise Specified: $AV_{DD} = DV_{DD} = 5V$, $FS = 6MHz$ (50% Duty Cycle),

$V_{RT} = 4.0$, $V_{RB} = 1.0$, $T_A = 25^{\circ}C$

| Parameter | Symbol | Min | 25°C Typ | Max | Units | Test Conditions/Comments | | |
|--|---------------------------------|-----------------|-------------|------------------|--------|---|----|----|
| KEY FEATURES | | | | | | | | |
| Resolution | | 10 | | | Bits | | | |
| Maximum Sampling Rate | FS | 6 | | | MHz | | | |
| ACCURACY (A Grade)¹ | | | | | | | | |
| Differential Non-Linearity | DNL | | | ±1 | LSB | Best Fit Line (Max INL – Min INL)/2 | | |
| Integral Non-Linearity | INL | | | ±2 | LSB | | | |
| Zero Scale Error | EZS | | 10 | | LSB | | | |
| Gain Error | EFS | | 6 | | LSB | | | |
| REFERENCE VOLTAGES | | | | | | | | |
| Positive Ref. Voltage ^{2,3} | V _{RT} | AGND 1.0 | 1400 | AV _{DD} | V | V _{REF} = V _{RT} – V _{RB} | | |
| Negative Ref. Voltage ^{2,3} | V _{RB} | | | | V | | | |
| Differential Ref. Voltage ^{2,3} | V _{REF} | | | AV _{DD} | V | | | |
| Ladder Resistance | R _L | | | | Ω | | | |
| Ladder Temp. Coefficient ² | R _{TCO} | | 2000 | | ppm/°C | V _{RT} connected to V _{RTS} & V _{RB} connected to V _{RBS} | | |
| Top Internal Reference | V _{RTS} | | 4 | | V | | | |
| Bottom Internal Reference | V _{RBS} | | 1 | | V | | | |
| ANALOG INPUT | | | | | | | | |
| Input Bandwidth (–1 dB) ^{2,4} | BW | V _{RB} | 25 | V _{RT} | MHz | | | |
| Input Voltage Range | V _{IN} | | | | V | | | |
| Input Capacitance (Sample) ^{2,5} | C _{IN} | | 25 | | 40 | | pF | |
| Input Capacitance (Convert) ^{2,5} | | | 7 | | 12 | | pF | |
| Aperture Delay ² | t _{AP} | | 25 | | 30 | | ns | |
| Aperture Uncertainty ² (Jitter) | t _{AJ} | | 50 | | | | ps | |
| DIGITAL INPUTS | | | | | | | | |
| Logical “1” Voltage | V _{IH} | 4 | 5 | 1 | V | V _{IN} =DGND to DV _{DD} | | |
| Logical “0” Voltage | V _{IL} | | | | | | V | |
| DC Leakage Currents ^{2,6} | I _{IN} | | | | | | μA | |
| CLK | | | | | 5 | | | μA |
| \overline{OE} | | | 5 | | μA | | | |
| Input Capacitance ² | | | 5 | | pF | | | |
| Clock Timing (See Figure 1) | | | | | | | | |
| Clock Period ² | 1/FS | | 167 | | ns | | | |
| Rise & Fall Time ^{2,7} | t _R , t _F | | 2 | | ns | | | |
| “High” Pulse Width ^{2,3} | t _{PWH} | | 84 | | ns | | | |
| “Low” Pulse Width ^{2,3} | t _{PWL} | | 84 | | ns | | | |
| Duty Cycle ^{2,3} | | | 50 | | % | | | |
| DIGITAL OUTPUTS | | | | | | | | |
| Logical “1” Voltage | V _{OH} | 4.5 | 10 | 0.4 | V | C _{OUT} =15 pF I _{LOAD} = 4mA I _{SINK} = 4mA V _{OUT} =DGND to DV _{DD} | | |
| Logical “0” Voltage | V _{OL} | | | | | | V | |
| 3-state Leakage | I _{OZ} | | | | | | μA | |
| Data Valid Delay | t _{DL} | | | | 40 | | ns | |
| Data Enable Delay | t _{DEN} | | | | 25 | | 30 | ns |
| Data 3-state Delay | t _{DHZ} | | | | 25 | | 30 | ns |

ELECTRICAL CHARACTERISTICS TABLE (CONT'D)

| Description | Symbol | Min | 25°C Typ | Max | Units | Conditions |
|---|----------|-----|-------------|-----|-------|------------|
| POWER SUPPLIES | | | | | | |
| Operating Voltage (V_{DD} , DV_{DD}) ^{8, 9} | V_{DD} | 4.5 | 5 | 5.5 | V | |
| Current (V_{DD} + DV_{DD}) | I_{DD} | | 13 | 17 | mA | |

Notes:

- ¹ Tester measures code transitions by dithering the voltage of the analog input (V_{IN}). The difference between the measured and the ideal code width ($V_{REF}/1024$) is the DNL error (Figure 3.). The INL error is the maximum distance (in LSBs) from the best fit line to any transition voltage (Figure 4.). Accuracy is a function of the sampling rate (FS).
- ² Guaranteed. Not tested.
- ³ Specified values guarantee functionality, but INL & DNL specifications may not be met.
- ⁴ -1 dB bandwidth is a measure of performance of the A/D input stage (S/H + amplifier). Refer to other parameters for accuracy within the specified bandwidth.
- ⁵ See V_{IN} equivalent circuit (Figure 8.). Switched capacitor analog input requires driver with low output resistance.
- ⁶ All inputs have diodes to DV_{DD} and DGND. Input DC currents will not exceed specified limits for any input voltage between DGND and DV_{DD} .
- ⁷ Condition to meet aperture delay specifications (t_{AP} , t_{AJ}). Actual rise/fall time can be less stringent with no loss of accuracy.
- ⁸ The AGND & DGND pins are connected through the silicon substrate. Connect together at the package and to the analog ground plane.
- ⁹ The V_{DD} & DV_{DD} pins should be tied together at the package.

Specifications are subject to change without notice

ABSOLUTE MAXIMUM RATINGS ($T_A = +25^\circ\text{C}$ unless otherwise noted)^{1, 2, 3}

| | | | |
|---------------------|-----------------------------|--|---------------|
| V_{DD} to AGND | +7V | Storage Temperature | -65 to +150°C |
| V_{RT} & V_{RB} | $V_{DD} + 0.5$ to GND -0.5V | Package Power Dissipation Rating to 75°C | |
| V_{IN} | $V_{DD} + 0.5$ to GND -0.5V | PDIP, SOIC | 1000mW |
| All Inputs | $V_{DD} + 0.5$ to GND -0.5V | Derates above 75°C | 14mW/°C |
| All Outputs | $V_{DD} + 0.5$ to GND -0.5V | Lead Temperature (Soldering 10 seconds) | +300°C |

Notes

- ¹ Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation at or above this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability.
- ² Any input pin which can see a value outside the absolute maximum ratings should be protected by Schottky diode clamps (HP5082-2835) from input pin to the supplies. All inputs have protection diodes which will protect the device from short transients outside the supplies of less than 100mA for less than 100µs.
- ³ V_{DD} refers to V_{DD} and DV_{DD} . GND refers to AGND and DGND.

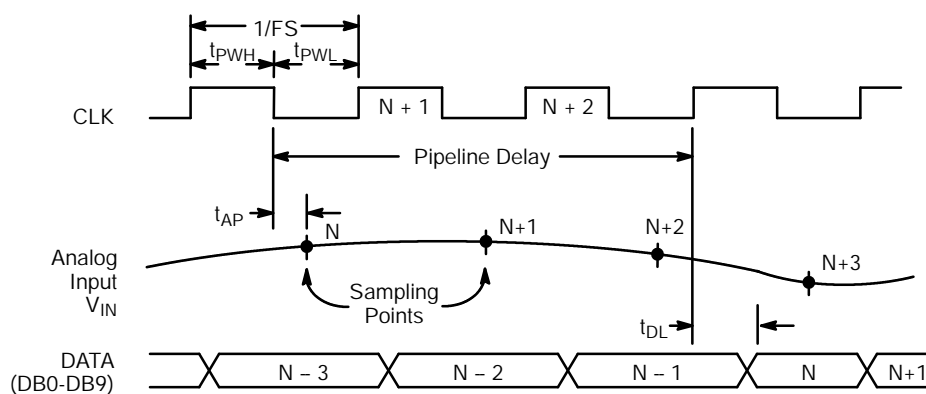


Figure 1. XRD6406 Timing Diagram

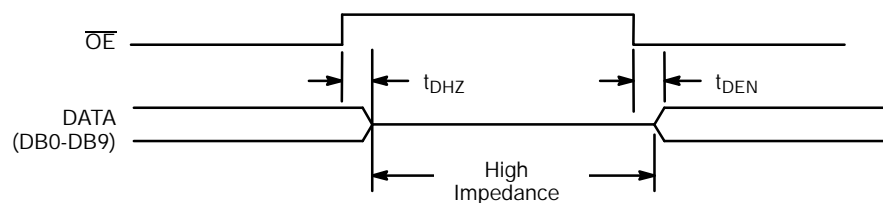


Figure 2. 3-State Timing Diagram

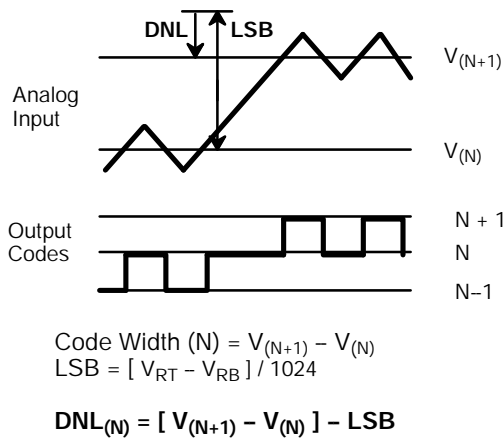


Figure 3. DNL Measurement

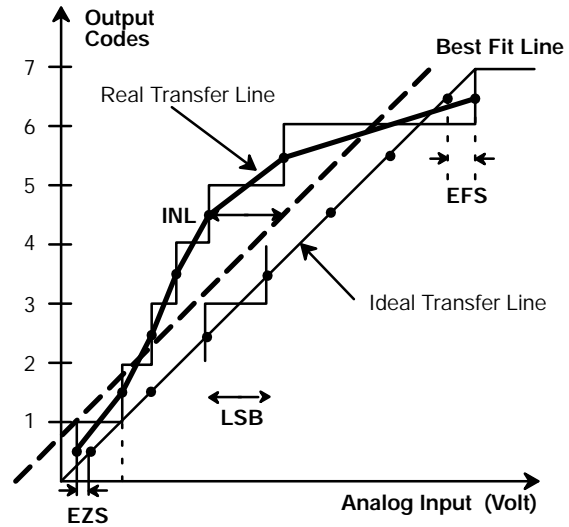


Figure 4. INL Error Calculation

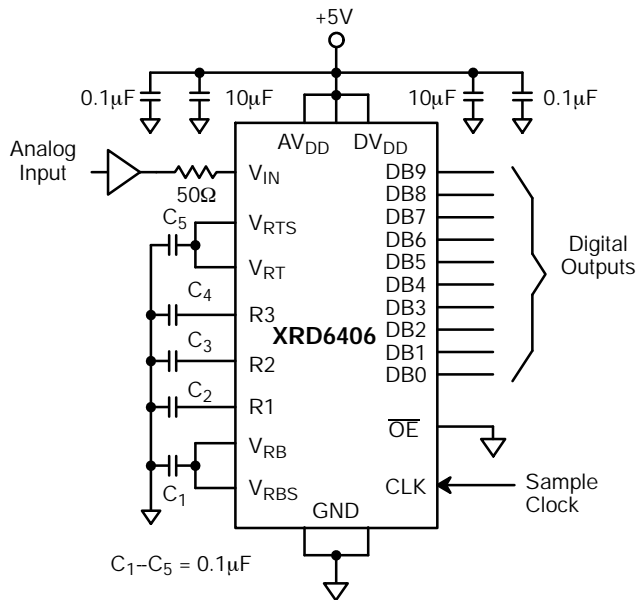


Figure 5. Typical Circuit Connections

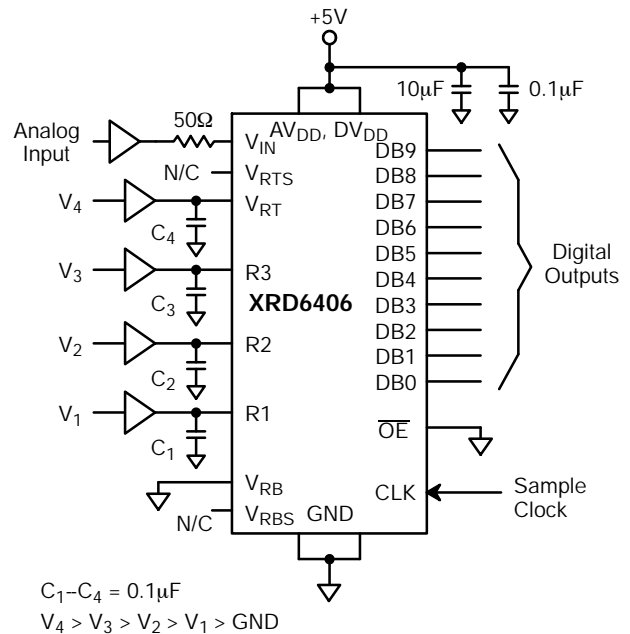


Figure 6. Creating a Piece Wise Linear Transfer Function

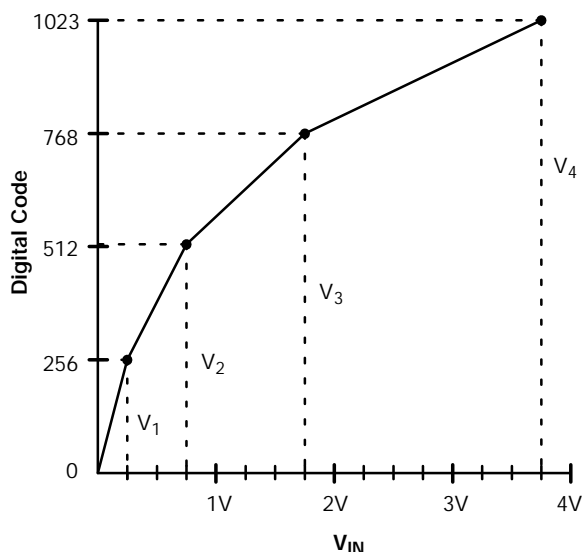


Figure 7. A Piece Wise Linear, Logarithmic Transfer Function

APPLICATION NOTES

Signals should not exceed AV_{DD} or $DV_{DD} + 0.5V$ or go below $DGND$ or $AGND - 0.5V$. All pins have internal protection diodes that will protect them from short transients ($< 100\mu s$) outside the supply range.

$AGND$ and $DGND$ pins are connected internally through the P-substrate. DC voltage differences between these pins will cause undesirable internal substrate currents.

The power supply (AV_{DD}) and reference voltage (V_{RT} & V_{RB}) pins should be decoupled with $0.1\mu F$ and $10\mu F$ capacitors to $AGND$, placed as close to the chip as possible.

The digital outputs should not drive long wires or buses. The capacitive coupling and reflections will contribute noise to the conversion.

V_{IN} Analog Input

This part has a switched capacitor type input circuit. This means that the input impedance changes with the phase of the input clock. V_{IN} is sampled at the high to low clock transition. Figure 8. shows an equivalent input circuit.

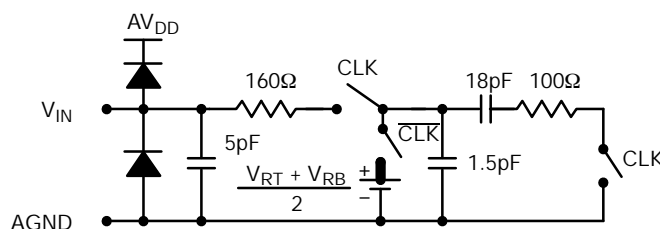


Figure 8. Equivalent Input Circuit

RTS & RBS Internal Bias Resistors

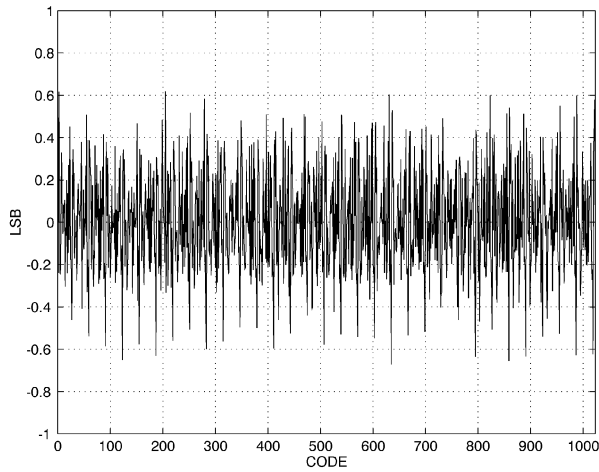
Two matched resistors are provided on the chip. These resistors can be used to generate on chip reference voltages. Each resistor has a value equal to 1/3 of the reference ladder resistor. By connecting RTS to V_{RT} , and connecting RBS to V_{RB} , the reference ladder will be biased to 1V at V_{RB} and 4V at V_{RT} .

If the internal reference pins V_{RTS} and/or V_{RBS} are not used they should be left unconnected.

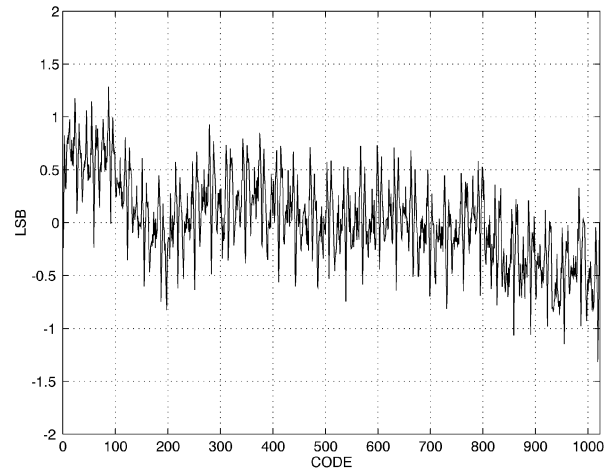
R1 thru R3 Reference Ladder Taps

These taps connect to every quarter point along the reference ladder; R1 is 1/4th up from V_{RB} , R3 is 3/4ths up from V_{RB} (or 1/4th down from V_{RT}). Normally these pins should have 0.1 microfarad capacitors to $AGND$; this helps reduce the INL errors by stabilizing the reference ladder voltages. These taps can also be used to alter the transfer curve of the ADC. A four segment, piecewise linear, custom transfer curve can be designed by connecting voltage sources to these pins.

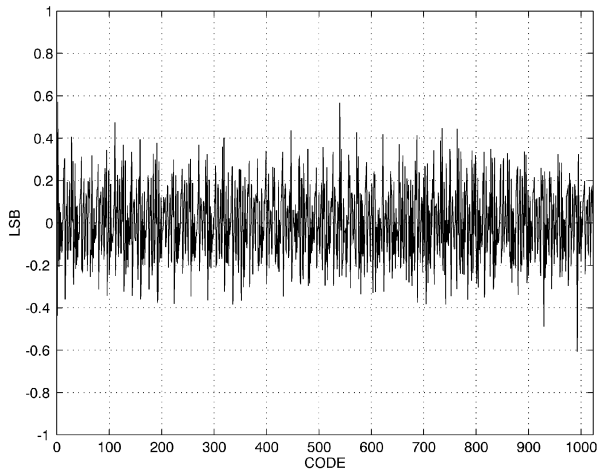
PERFORMANCE CHARACTERISTICS



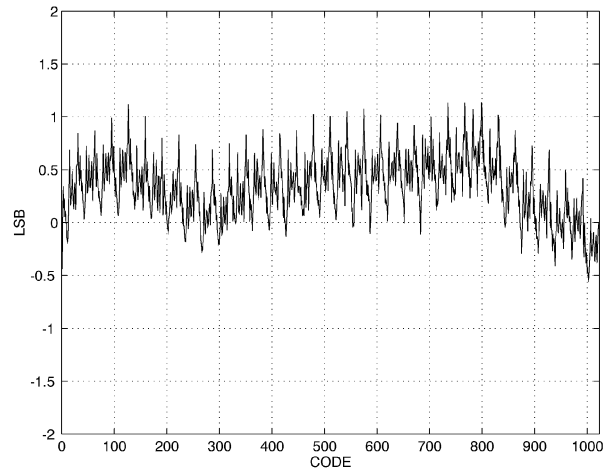
Graph 1. XRD6406, DNL @ 5MSPS
 $DV_{DD} = 5V$, $AV_{DD} = 5V$, $V_{RT} = 4V$, $V_{RB} = 1V$



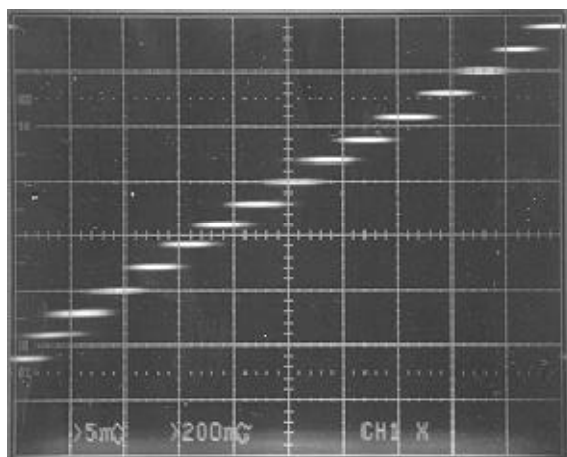
Graph 2. XRD6406, INL @ 5MSPS
 $DV_{DD} = 5V$, $AV_{DD} = 5V$, $V_{RT} = 4V$, $V_{RB} = 1V$



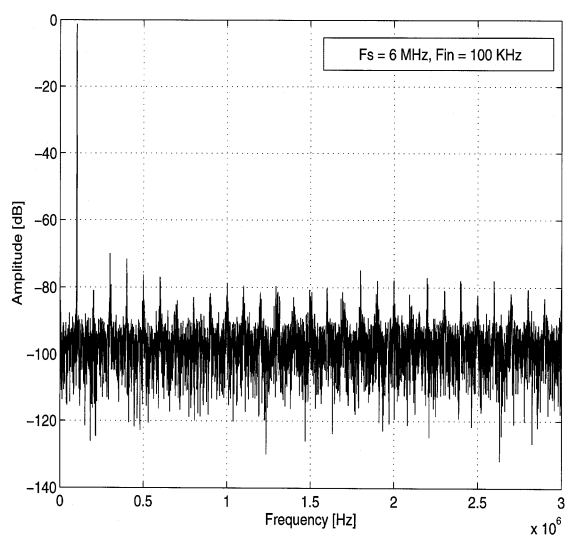
Graph 3. XRD6406, DNL @ 5MSPS
 $DV_{DD} = 3V$, $AV_{DD} = 5V$, $V_{RT} = 4.5V$, $V_{RB} = 0.5V$



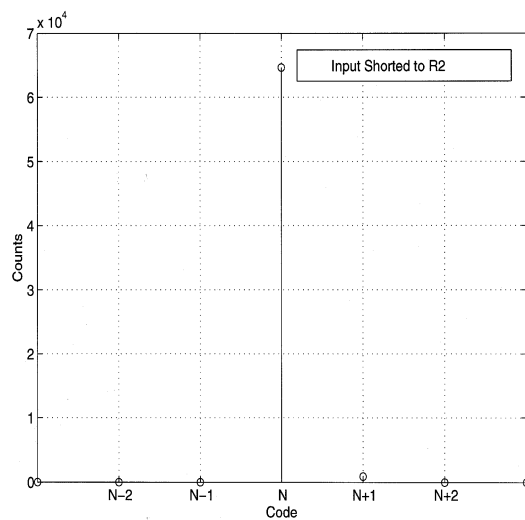
Graph 4. XRD6406, INL @ 5MSPS
 $DV_{DD} = 3V$, $AV_{DD} = 5V$, $V_{RT} = 4.5V$, $V_{RB} = 0.5V$



Graph 5. Crossplot Staircase Output
CLK = 6MSPS, $V_{REF} = 4V$



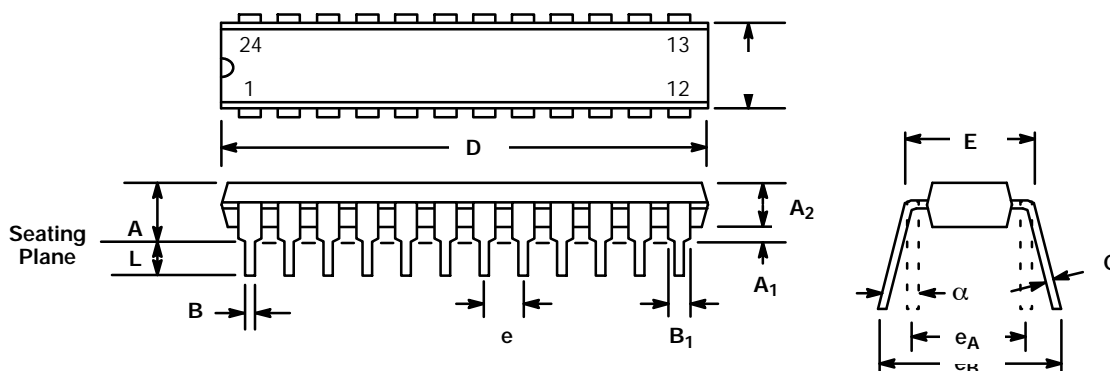
Graph 6. XRD6406 Spectral Performance



Graph 7. XRD6406 Output Noise Histogram

24 LEAD PLASTIC DUAL-IN-LINE (300 MIL PDIP)

Rev. 1.00

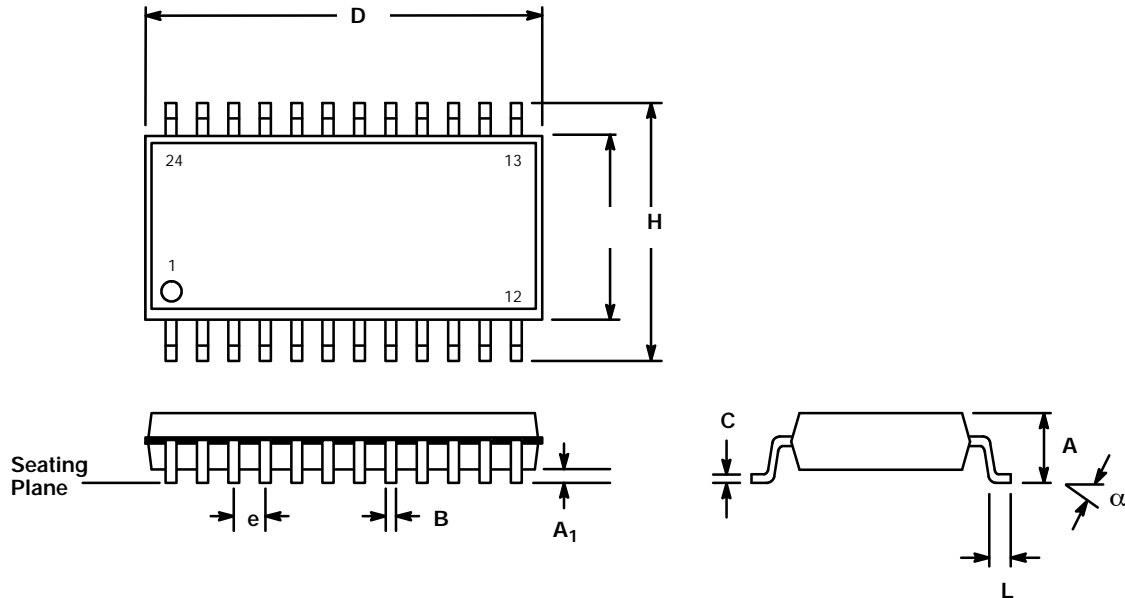


| SYMBOL | INCHES | | MILLIMETERS | |
|----------------|-----------|-------|-------------|-------|
| | MIN | MAX | MIN | MAX |
| A | 0.145 | 0.210 | 3.68 | 5.33 |
| A ₁ | 0.015 | 0.070 | 0.38 | 1.78 |
| A ₂ | 0.115 | 0.195 | 2.92 | 4.95 |
| B | 0.014 | 0.024 | 0.36 | 0.56 |
| B ₁ | 0.030 | 0.070 | 0.76 | 1.78 |
| C | 0.008 | 0.014 | 0.20 | 0.38 |
| D | 1.125 | 1.275 | 28.58 | 32.39 |
| E | 0.300 | 0.325 | 7.62 | 8.26 |
| E ₁ | 0.240 | 0.280 | 6.10 | 7.11 |
| e | 0.100 BSC | | 2.54 BSC | |
| e _A | 0.300 BSC | | 7.62 BSC | |
| e _B | 0.310 | 0.430 | 7.87 | 10.92 |
| L | 0.115 | 0.160 | 2.92 | 5.08 |
| α | 0° | 15° | 0° | 15° |

Note: The control dimension is the inch column

**24 LEAD SMALL OUTLINE
(300 MIL JEDEC SOIC)**

Rev. 1.00



| SYMBOL | INCHES | | MILLIMETERS | |
|--------|-----------|-------|-------------|-------|
| | MIN | MAX | MIN | MAX |
| A | 0.093 | 0.104 | 2.35 | 2.65 |
| A1 | 0.004 | 0.012 | 0.10 | 0.30 |
| B | 0.013 | 0.020 | 0.33 | 0.51 |
| C | 0.009 | 0.013 | 0.23 | 0.32 |
| D | 0.598 | 0.614 | 15.20 | 15.60 |
| E | 0.291 | 0.299 | 7.40 | 7.60 |
| e | 0.050 BSC | | 1.27 BSC | |
| H | 0.394 | 0.419 | 10.00 | 10.65 |
| L | 0.016 | 0.050 | 0.40 | 1.27 |
| α | 0° | 8° | 0° | 8° |

Note: The control dimension is the millimeter column

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